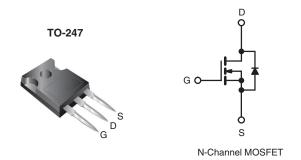


Power MOSFET

PRODUCT SUMMARY					
V _{DS} (V)	25	250			
$R_{DS(on)}\left(\Omega\right)$	V _{GS} = 10 V	0.28			
Q _g (Max.) (nC)	6	63			
Q _{gs} (nC)	1	12			
Q _{gd} (nC)	3	39			
Configuration	Sir	Single			



FEATURES

- · Dynamic dV/dt Rating
- · Repetitive Avalanche Rated
- · Isolated Central Mounting Hole
- Fast Switching
- Simple Drive Requirements
- Lead (Pb)-free Available



DESCRIPTION

Third generation Power MOSFETs from Vishay provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The TO-247 package is preferred for commercial-industrial applications where higher power levels preclude the use of TO-220 devices. The TO-247 is similar but superior to the earlier TO-218 package because of its isolated mounting hole. It also provides greater creepage distance between pins to meet the requirements of most safety specifications.

ORDERING INFORMATION		
Package	TO-247	
Lead (Pb)-free	IRFP244PbF	
Lead (FD)-life	SiHFP244-E3	
SnPb	IRFP244	
SILL	SiHFP244	

PARAMETER	SYMBOL	LIMIT	UNIT	
Drain-Source Voltage	V_{DS}	250	V	
Gate-Source Voltage	V_{GS}	± 20	V	
Continuous Drain Current	V_{GS} at 10 V $T_{C} = 25 ^{\circ}C$ $T_{C} = 100 ^{\circ}C$	l _D	15	А
	$T_{\rm C} = 100 ^{\circ}$		9.7	
Pulsed Drain Current ^a	I _{DM}	60		
Linear Derating Factor		1.2	W/°C	
Single Pulse Avalanche Energy ^b	E _{AS}	550	mJ	
Repetitive Avalanche Current ^a	I _{AR}	15	Α	
Repetitive Avalanche Energy ^a		E _{AR}	15	mJ
Maximum Power Dissipation	T _C = 25 °C	P_{D}	150	W
Peak Diode Recovery dV/dt ^c	dV/dt	4.8	V/ns	
Operating Junction and Storage Temperature Range	T_J,T_stg	- 55 to + 150	°C	
Soldering Recommendations (Peak Temperature)	for 10 s	-	300 ^d	
Mounting Torque	6-32 or M3 screw		10	lbf ⋅ in
	6-32 OF IVIS SCIEW		1.1	N · m

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. V_{DD} = 50 V, starting T_J = 25 °C, L = 3.9 mH, R_G = 25 Ω , I_{AS} = 15 A (see fig. 12).
- c. $I_{SD} \leq$ 15 A, $dI/dt \leq$ 150 A/µs, $V_{DD} \leq V_{DS}, \, T_{J} \leq$ 150 °C.
- d. 1.6 mm from case.

^{*} Pb containing terminations are not RoHS compliant, exemptions may apply



THERMAL RESISTANCE RATINGS				
PARAMETER	SYMBOL	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient	R _{thJA}	-	40	
Case-to-Sink, Flat, Greased	R _{thCS}	0.24	-	°C/W
Maximum Junction-to-Case (Drain)	R _{thJC}	-	0.83	

PARAMETER	SYMBOL	TEST	TEST CONDITIONS		TYP.	MAX.	UNIT
Static							
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		250	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference to 25 °C, I _D = 1 mA		-	0.37	-	V/°C
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V$	$V_{DS} = V_{GS}, I_D = 250 \mu A$		-	4.0	V
Gate-Source Leakage	I _{GSS}	V _{GS} = ± 20 V		-	-	± 100	nA
Zero Gate Voltage Drain Current	I _{DSS}	$V_{DS} = 250 \text{ V}, V_{GS} = 0 \text{ V}$ $V_{DS} = 200 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 125 \text{ °C}$		-	-	25 250	μΑ
Drain-Source On-State Resistance	R _{DS(on)}	$V_{DS} = 200 \text{ V}, \text{ V}$ $V_{GS} = 10 \text{ V}$	I _D = 9.0 A ^b	-	-	0.28	Ω
Forward Transconductance	9fs		0 V, I _D = 9.0 A ^b	6.7	_	-	S
Dynamic	J13		- , , , , , ,				
Input Capacitance	C _{iss}	$V_{GS} = 0 \text{ V},$ $V_{DS} = 25 \text{ V},$ $f = 1.0 \text{ MHz}, \text{ see fig. 5}$		_	1400	_	pF
Output Capacitance	C _{oss}			-	320	-	
Reverse Transfer Capacitance	C _{rss}			-	73	-	
Total Gate Charge	Qg		$V_{GS} = 10 \text{ V}$ $I_D = 11 \text{ A}, V_{DS} = 200 \text{ V},$ see fig. 6 and 13 ^b	-	-	63	nC
Gate-Source Charge	Q _{gs}	V _{GS} = 10 V		-	-	12	
Gate-Drain Charge	Q _{gd}			-	-	39	
Turn-On Delay Time	t _{d(on)}			-	14	-	- ns
Rise Time	t _r	V _{DD} = 13	V 105 V L 11 A		49	-	
Turn-Off Delay Time	t _{d(off)}	$V_{DD} = 125 \text{ V, } I_D = 11 \text{ A },$ $R_G = 9.1 \ \Omega, \ R_D = 11 \ \Omega, \text{ see fig. } 10^b$		-	42	-	
Fall Time	t _f			-	24	-	
Internal Drain Inductance	L _D	Between lead, 6 mm (0.25") from package and center of die contact		-	5.0	-	
Internal Source Inductance	L _S			-	13	-	- nH
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	Is	MOSFET symbol showing the integral reverse p - n junction diode		-	-	15	
Pulsed Diode Forward Current ^a	I _{SM}			-	-	60	A
Body Diode Voltage	V _{SD}	T _J = 25 °C, I _S = 15 A, V _{GS} = 0 V ^b		-	-	1.8	V
Body Diode Reverse Recovery Time	t _{rr}	T _J = 25 °C, I _F = 11 A, dl/dt = 100 A/μs ^b		-	290	570	ns
Body Diode Reverse Recovery Charge	Q _{rr}			-	3.1	6.3	μC
Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negligible (turn-			ninated b	y L _S and	L _D)

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. Pulse width \leq 300 μ s; duty cycle \leq 2 %.



TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

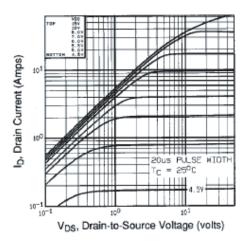


Fig. 1 - Typical Output Characteristics, T_C = 25 °C

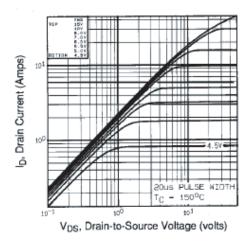


Fig. 2 - Typical Output Characteristics, T_C = 150 °C

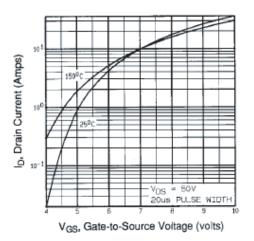


Fig. 3 - Typical Transfer Characteristics

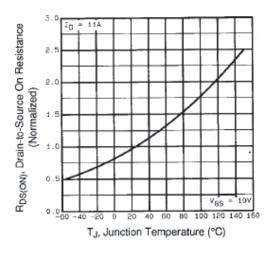


Fig. 4 - Normalized On-Resistance vs. Temperature



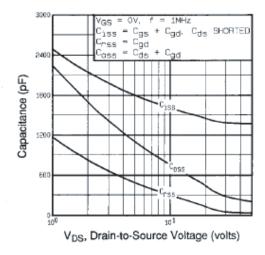


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

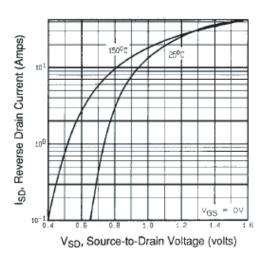


Fig. 7 - Typical Source-Drain Diode Forward Voltage

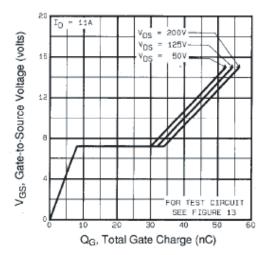


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

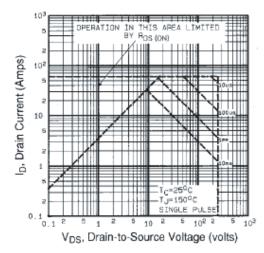
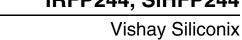


Fig. 8 - Maximum Safe Operating Area





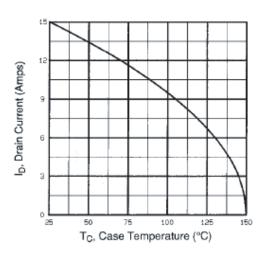


Fig. 9 - Maximum Drain Current vs. Case Temperature

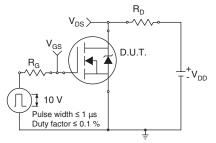


Fig. 10a - Switching Time Test Circuit

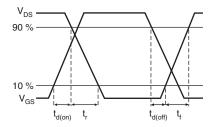


Fig. 10b - Switching Time Waveforms

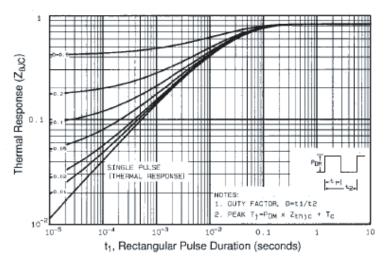


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case



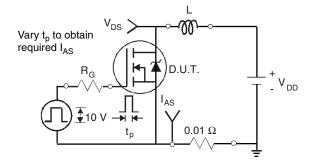


Fig. 12a - Unclamped Inductive Test Circuit

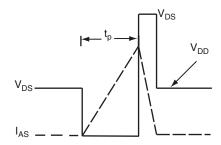


Fig. 12b - Unclamped Inductive Waveforms

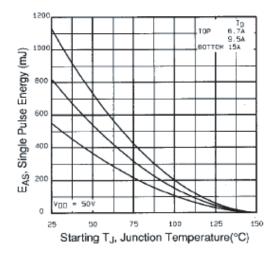


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

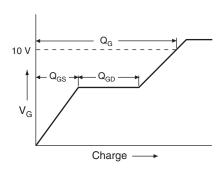


Fig. 13a - Basic Gate Charge Waveform

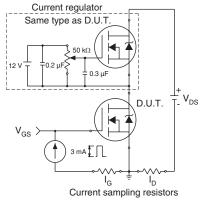
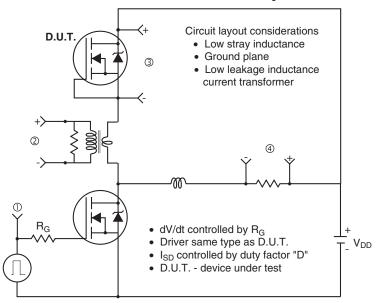
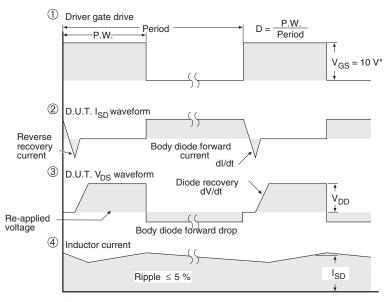


Fig. 13b - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit





* $V_{GS} = 5 V$ for logic level devices

Fig. 14 - For N-Channel

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